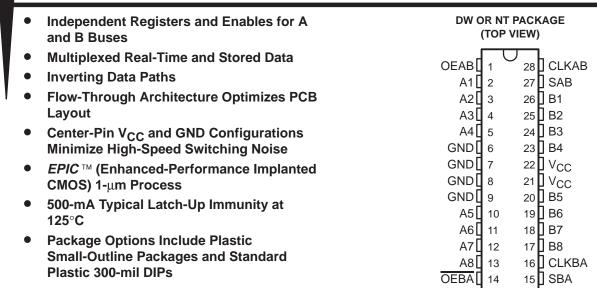
74AC11651 OCTAL BUS TRANSCEIVER AND REGISTER WITH 3-STATE OUTPUTS

SCAS135 - MARCH 1990 - REVISED APRIL 1993



description

These devices consist of bus transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Output-enable (OEAB and OEBA) inputs are provided to control the transceiver functions. The select-control (SAB and SBA) inputs are provided to select whether real-time or stored data is transferred. A low input level selects real-time data, and a high input level selects stored data. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the 74AC11651.

Data on the A or B bus, or both, can be stored in the internal D flip-flops by low-to-high transitions at the appropriate clock (CLKAB or CLKBA) inputs regardless of the select- or enable-control pins. When SAB and SBA are in the real-time transfer mode, it is also possible to store data without using the internal D-type flip-flops by simultaneously enabling OEAB and OEBA. In this configuration, each output reinforces its input. Thus, when all the other data sources to the two sets of bus lines are at high impedance, each set will remain at its last state.

The 74AC11651 is characterized for operation from -40°C to 85°C.

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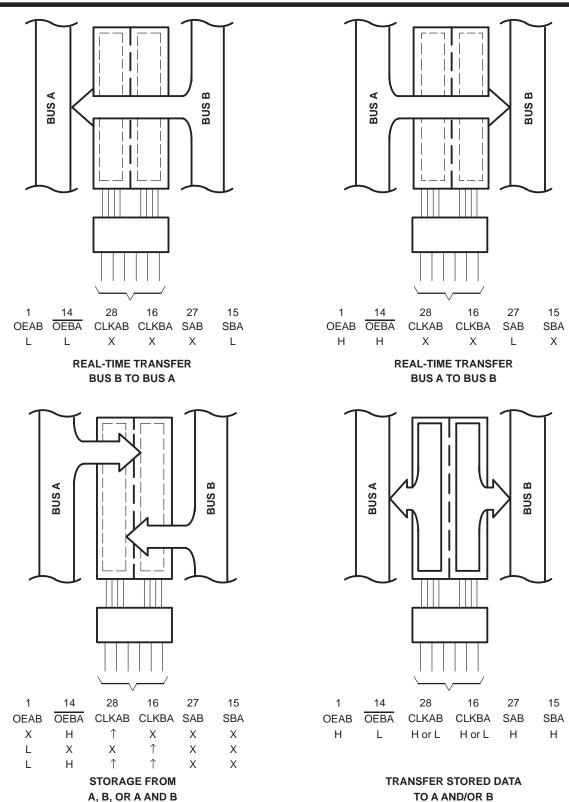


Figure 1. Bus-Management Functions



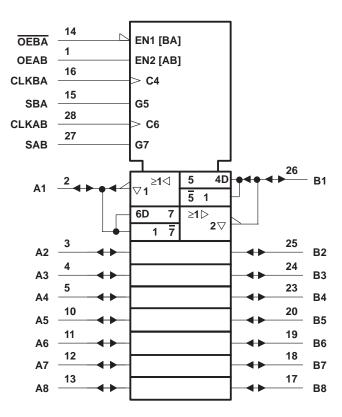
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FUNCTION TABLE

	INPUTS DATA I/O				ODEDATION OF EUNOTION			
OEAB	OEBA	CLKAB	CLKBA	SAB	SBA	A1 THRU A8	B1 THRU B8	OPERATION OR FUNCTION
L	Н	H or L	H or L	Х	Х	Input	Input	Isolation
L	Н	\uparrow	\uparrow	X	X	Input	Input	Store A and B data
Х	Н	\uparrow	H or L	X	X	Input	Unspecified [†]	Store A, hold B
Н	Н	\uparrow	\uparrow	X‡	X	Input	Output	Store A in both registers
L	X	H or L	\uparrow	X	X	Unspecified [†]	Input	Hold A, store B
L	L	\uparrow	\uparrow	X	X‡	Output	Input	Store B in both registers
L	L	X	Χ	X	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	X	Н	Output	Output	Stored B data to A bus
Н	Н	X	Χ	L	X	Input	Output	Real-time A data to B bus
Н	Н	H or L	Χ	Н	X	Input	Output	Stored A data to B bus
Н	L	H or L	H or L	Н	Н	Output	Output	Stored A data to B bus and stored B data to A bus

[†] The data output functions may be enabled or disabled by various signals at the OEAB or OEBA inputs. Data input functions are always enabled, i.e., data at the bus pins will be stored on every low-to-high transition on the clock inputs.

logic symbol§



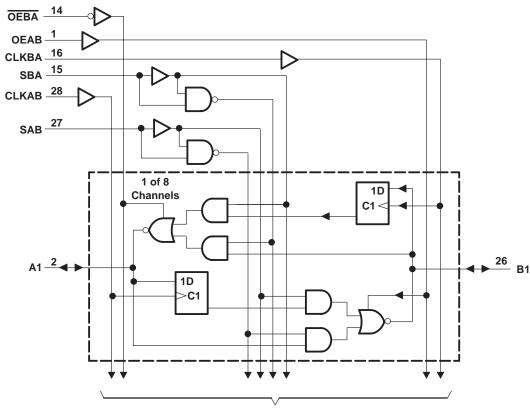
§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



[‡] When select control is low, clocks can occur simultaneously so long as allowances are made for propagation delays from A to B (B to A) plus setup and hold times. When select control is high, clocks must be staggered in order to load both registers.

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logic diagram (positive logic)



To 7 Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	$-0.5 \text{ V to } 7$	V
Input voltage range, V _I (see Note 1)	$5 \text{ V to V}_{CC} + 0.5$	٧
Output voltage range, V _O (see Note 1)	$5 \text{ V to V}_{CC} + 0.5$	٧
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 m	١A
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 m	١A
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 m	١A
Continuous current through V _{CC} or GND pins	±200 m	١A
Storage temperature range	. −65°C to 150°	Ċ

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



recommended operating conditions

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		3	5	5.5	V
		V _{CC} = 3 V	2.1			
V_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			V
		V _{CC} = 5.5 V	3.85			
		V _{CC} = 3 V			0.9	
VIL	Low-level input voltage V _{CC} = 4.5 V				1.35	V
		V _{CC} = 5.5 V			1.65	
٧ _I	Input voltage		0		VCC	V
٧o	Output voltage		0		Vcc	V
		V _{CC} = 3 V			-4	
ІОН	High-level output current	V _{CC} = 4.5 V			-24	mA
VIH VIL VI VO		V _{CC} = 5.5 V			-24	
		V _{CC} = 3 V			12	
lOL	Low-level output current	V _{CC} = 4.5 V			24	mA
				24		
Δt/Δν	Input transition rise or fall rate		0		10	ns/V
TA	Operating free-air temperature		-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DA	DAMETER	TEST CONDITIONS	V	T _A = 25°C			MIN	MAV	LIMIT
PA	RAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	IVIIN	0.1 0.1 0.44 0.44 1.65 ±1	UNIT
			3 V	2.9			2.9		
		I _{OH} = -50 μA	4.5 V	4.4			4.4		
			5.5 V	5.4			5.4		
Vон		I _{OH} = – 4 mA	3 V	2.58			2.48		V
			4.5 V	3.94			3.8		
		IOH = - 24 mA	5.5 V	4.94			4.8		
		I _{OH} = -75 mA [†]	5.5 V				3.85		
			3 V			0.1		0.1	
		I _{OL} = 50 μA	4.5 V			0.1		0.1	
			5.5 V			0.1		0.1	
VOL		I _{OL} = 12 mA	3 V			0.36		0.44	V
		1- 04 mA	4.5 V			0.36		0.44	
		I _{OL} = 24 mA	5.5 V			0.36		0.44	1
		I _{OL} = 75 mA [†]	5.5 V					1.65	
ΙĮ	Control inputs	V _I = V _{CC} or GND	5.5 V			±0.1		±1	μΑ
loz‡	A or B ports	V _O = V _{CC} or GND	5.5 V			±0.5		±5	μΑ
ICC		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μΑ
Ci	Control inputs	$V_I = V_{CC}$ or GND	5 V		4.5				pF
C _{io}	A or B ports	$V_O = V_{CC}$ or GND	5 V		10				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡] For I/O ports, the parameter IOz includes the input leakage current.



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timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 2)

		$T_A = 2$	25°C	MIN	MAX	UNIT
		MIN	MAX	IVIIIV		ONIT
fclock	Clock frequency	0	45	0	45	MHz
t _W	Pulse duration, CLK high or low	10		10		ns
t _{su}	Setup time, A or B before CLKAB↑ or CLKBA↑	6.5		6.5		ns
t _h	Hold time, A or B after CLKAB↑ or CLKBA↑	0		0		ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 2)

		$T_A = 2$	25°C	MIN	MAX	UNIT
		MIN	MAX	IVIIIV		ONIT
fclock	Clock frequency	0	90	0	90	MHz
t _W	Pulse duration, CLK high or low	5.5		5.5		ns
t _{su}	Setup time, A or B before CLKAB↑ or CLKBA↑	4.5		4.5		ns
th	Hold time, A or B after CLKAB↑ or CLKBA↑	0.5		0.5		ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	то	T _A = 25°C			MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	IVIAA	UNII
f _{max}			45			45		MHz
t _{PLH}	A or B	B or A	3.2	7.7	12.1	3.2	14	ns
^t PHL		BUIA	4.3	9.5	14.6	4.3	16.1	115
^t PLH	CLKBA or CLKAB	A or B	4.6	9.8	15	4.6	17.2	ns
^t PHL	CLKBA or CLKAB	AUIB	5.4	11.5	17.5	5.4	19.2	115
^t PLH	SBA or SAB† (A or B high)	A on D	3.8	8.6	13.3	3.8	15.3	
^t PHL		A or B	4.8	10.2	15.5	4.8	17.1	ns
^t PLH	SBA or SABT	A D	3.4	8.1	12.7	3.4	14.6	
^t PHL	(A or B low)	A or B	5	10.3	15.5	5	17.1	ns
^t PZH	OEBA	А	4.6	9.8	14.9	4.6	16.9	ns
^t PZL	OEBA		5.3	12.1	18.9	5.3	21.3	
^t PHZ	OEBA	Δ	4.4	6.6	8.8	4.4	9.2	
^t PLZ	UEBA	A	3.8	5.8	7.8	3.8	8.1	ns
^t PZH	OEAR	В	4.9	10.2	15.5	4.9	17.6	
t _{PZL}	OEAB	В	5.5	12.2	18.8	5.5	21.2	ns
^t PHZ	OEAB	В	4.4	6.7	8.9	4.4	9.3	20
^t PLZ	UEAD	D	3.5	5.7	7.8	3.5	8	ns

[†] These parameters are measured with the internal output state of the storage register opposite to that of the bus input.



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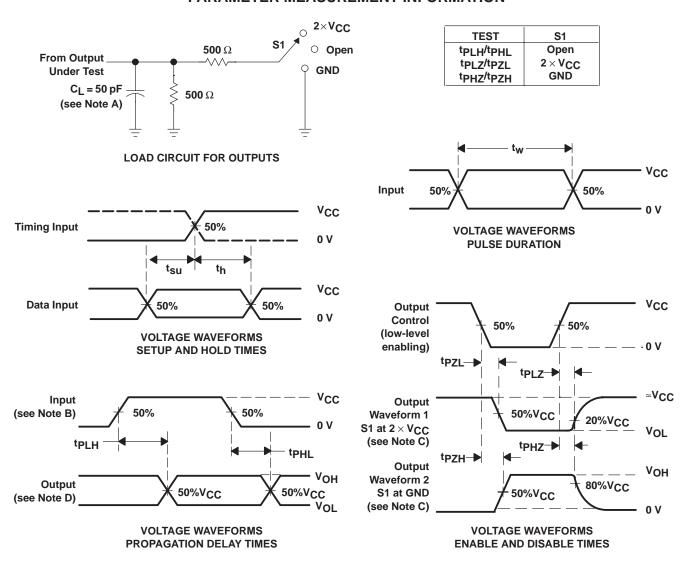
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	то	T,	Վ = 25° C	;	MIN M	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	WAX	UNIT
f _{max}			90			90		MHz
t _{PLH}	A or B	B or A	2.6	5.3	8	2.6	9.1	ns
t _{PHL}		BUIA	3.5	6.5	9.4	3.5	10.5	115
^t PLH	CLKBA or CLKAB	A or B	3.8	6.8	10	3.8	11.4	ns
t _{PHL}		AUID	4.7	8.1	11.5	4.7	12.8	115
t _{PLH}	SBA or SAB [†] (A or B high)	A or B	3.2	6	8.8	3.2	10.1	ns
t _{PHL}		AUID	3.9	7	10.1	3.9	11.2	115
^t PLH	SBA or SAB [†]	A or B	2.9	5.7	8.5	2.9	9.5	ns
^t PHL	(A or B low)	AUID	4.1	7.2	10.3	4.1	11.4	115
^t PZH	OEBA	А	3.9	6.9	9.8	3.9	11.1	ns
tPZL	OEBA	A	4.2	7.6	11	4.2	12.5	115
^t PHZ	OEBA	A	4.1	5.9	7.6	4.1	8	ns
tPLZ	OEBA	A	3.5	5.2	6.8	3.5	7.1	115
^t PZH	OEAB	В	4.2	5.9	10.4	4.2	11.8	
tPZL	OEAB	D	4.5	8	11.4	4.5	12.9	ns
^t PHZ	OEAB	В	4.2	6	7.8	4.2	8.2	20
t _{PLZ}	VEAD	D	3.3	5.1	6.9	3.3	7.2	ns

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER			TEST CO	TYP	UNIT	
C _{pd}	Dower dissination conscitance per transcriver	Outputs enabled	C 50 pF	f = 1 MHz	64	pF
	Power dissipation capacitance per transceiver	Outputs disabled	$C_L = 50 \text{ pF},$	f = 1 MHz	14	þΓ

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \ \Omega$, $t_f \leq 3$ ns, $t_f \leq 3$ ns. For testing pulse duration: $t_f = t_f = 1$ to 3 ns. Pulse polarity can be either high-to-low-to-high or low-to-high-to-low.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms



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